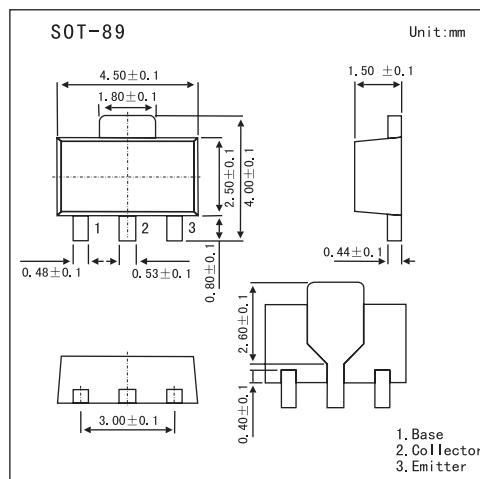


■ Features

- Adoption of FBET, MBIT Processes
- High Breakdown Voltage and Large Current Capacity



■ Absolute Maximum Ratings Ta = 25°C

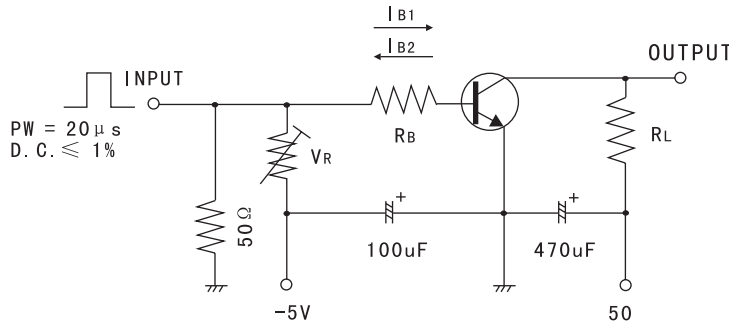
Parameter	Symbol	Rating	Unit
Collector-Base Voltage	V _{CB0}	120	V
Collector-Emitter Voltage	V _{CEO}	100	V
Emitter-Base Voltage	V _{EBO}	6	V
Collector Current	I _C	2	A
Collector Current (Pulse)	I _{CP}	3	A
Collector Power Dissipation	P _C	500	mW
	P _C *	1.5	W
Junction temperature	T _j	150	°C
Storage temperature Range	T _{stg}	-55 to +150	°C

* Mounted on ceramic board (250 mm² x 0.8 mm)

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Testconditions	Min	Typ	Max	Unit
Collector Cut-off Current	I _{CBO}	V _{CB} = 100V , I _E = 0			100	nA
Emitter Cut-off Current	I _{EBO}	V _{EB} = 4V , I _C = 0			100	nA
Collector-Base Breakdown Voltage	V _{(BR)CBO}	I _C = 10μA , I _E = 0	120			V
Collector-Emitter Breakdown Voltage	V _{(BR)CEO}	I _C = 1mA , R _{BE} = ∞	100			V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	I _E = 10μA , I _C = 0	6			V
DC Current Gain	h _{FE}	V _{CE} = 5V , I _C = 100mA	100		400	
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C = 1A , I _B = 100mA		0.22	0.6	V
Base-Emitter Saturation Voltage	V _{BE(sat)}	I _C = 1A , I _B = 100mA		0.85	1.2	V
Gain-Bandwidth Product	f _T	V _{CE} = 10V , I _C = 100mA		120		MHz
Collector Output Capacitance	C _{ob}	V _{CB} = 10V , I _E = 0 , f = 1MHz		25		pF
Turn-On Time	t _{on}	See Test Circuit.		80		ns
Storage Time	t _{stg}			750		
Fall Time	t _f			40		

■ Test Circuit

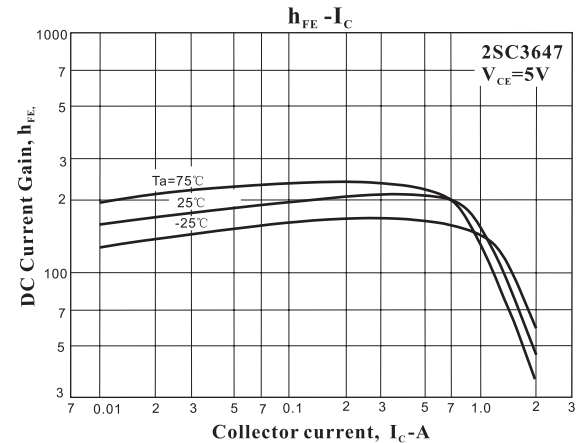
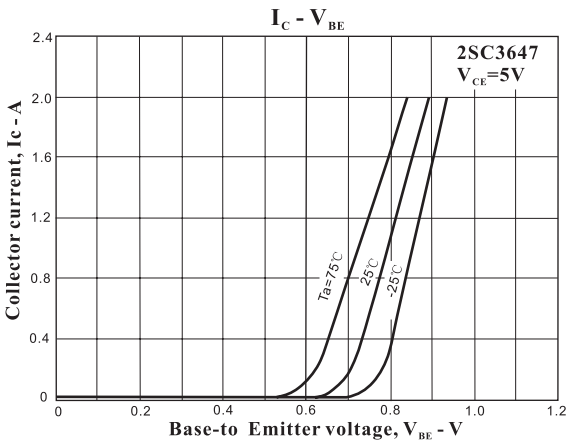
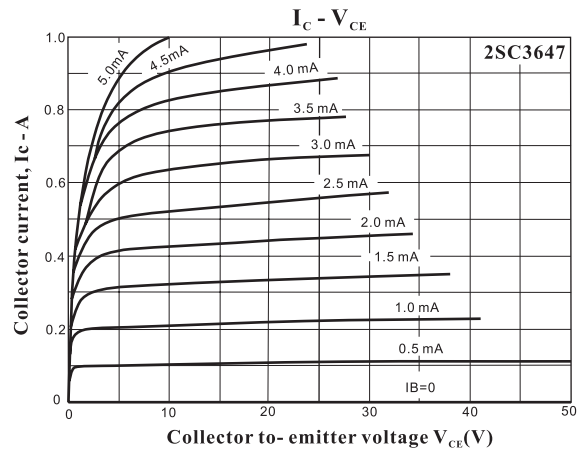
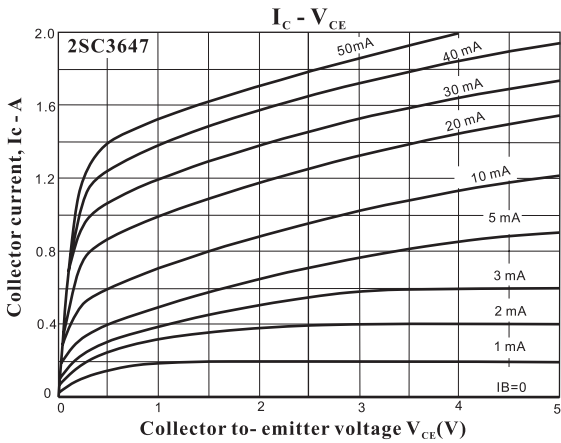


$10I_{B1} = -10I_{B2} = I_C = 0.7A$
 (For PNP, the polarity is reversed.)

■ hFE Classification

Marking	CC		
Rank	R	S	T
hFE	100 ~ 200	140 ~ 280	200 ~ 400

■ Electrical Characteristics Curves





2SC3647

